

# **VDIC NAND Flash Memory**

## **VDNF32G08XS50XX8V25 USER MANUAL**

**Version : A5**

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# VDIC-NAND Flash Memory

## HIGH-SPEED 3.3V 4G×8bit

### 1. DESCRIPTION

Offered in 4Gx8bit, the VDNF32G08XS50XX8V25 is a 32G-bit NAND Flash Memory with spare capacity of 128M-bits. The device operates at 3.3V. The I/O pins serve as the ports for address and data input/output as well as command input.

The VDNF32G08XS50XX8V25 device is stacked with eight dies. The operation of each die operates independently. The I/O ports and the control pins (ALE,CLE,#WE,#RE) of all banks in each die are connected.

A program operation can be performed in typical 200μs on the (2K+64)Byte page and an erase operation can be performed in typical 1.5ms on a (128K+4K)Byte block. Data in the data register can be read out at 25ns cycle time per Byte.

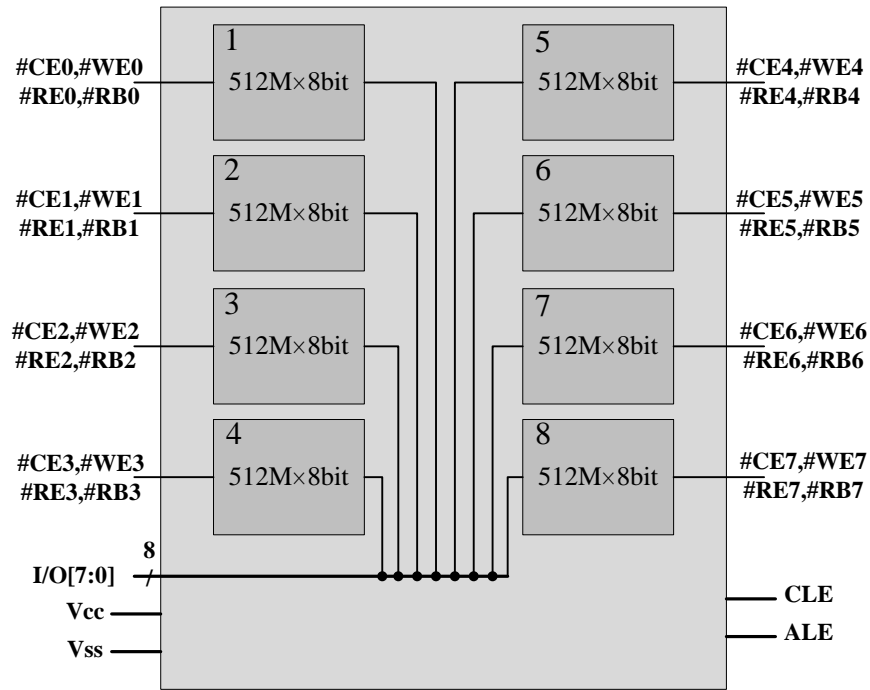
Every die has an on-chip write controller which is used to automate all program and erase functions including pulse repetition, where required, and internal verification and margining of data. Even the write-intensive systems can take advantage of the VDNF32G08XS50XX8V25's extended reliability of 100K program/erase cycles by providing ECC(Error Correcting Code) with real time mapping-out algorithm.

Its NAND cell provides the most cost-effective solution for the solid state application market. The VDNF32G08XS50XX8V25 is an optimum solution for large nonvolatile storage applications such as solid state data storage and advanced embedded control applications.

## 2. FEATURES

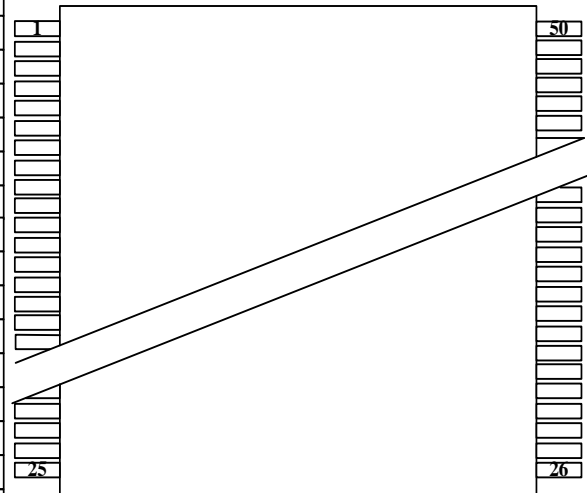
- Voltage Supply
  - 3.3V device: 2.7 ~ 3.6 V
- Organization
  - Memory Cell Array
    - 8Dies x (512M + 8M) Byte x 8 bit
  - Data Register for each bank
    - (2K + 64) Byte x 8bit
- Automatic Program and Erase
  - Page Program for each bank
    - (2K + 64)Byte
  - Block Erase for each bank
    - (128K + 4K)Byte
- Page Read Operation for each bank
  - Page Size
    - (2K + 64)Byte
  - Random Access : 25 $\mu$ s(Max.)
  - Serial Page Access : 25ns(Min.)
- Fast Write Cycle Time
  - Program time : 200 $\mu$ s(Typ.)
  - Block Erase Time : 1.5ms(Typ.)
- Command/Address/Data Multiplexed I/O Port
- Hardware Data Protection
  - Program/Erase Lockout During Power Transitions
- Reliable CMOS Floating-Gate Technology
  - Endurance : 100K Program/Erase Cycles
  - Data Retention : 10 Years
- Command Register Operation
- Intelligent Copy-Back with internal 1bit/528Byte EDC
- Package SOP-50

### 3. BLOCK DIAGRAM



## 4. PIN DESCRIPTIONS– SOP-50

Pin Id	Pin #		Pin Id
#RB7	1	50	#RE7
#RB6	2	49	#RE6
#RB5	3	48	#RE5
#RB4	4	47	#RE4
#R/B3	5	46	#RE3
#R/B2	6	45	I/O7
#R/B1	7	44	I/O6
#R/B0	8	43	I/O5
#RE0	9	42	I/O4
#CE0	10	41	#RE2
#CE1	11	40	#RE1
#CE2	12	39	VCC
VCC	13	38	VCC
VSS	14	37	VSS
#CE3	15	36	VSS
#CE4	16	35	VSS
CLE	17	34	#CE5
ALE	18	33	I/O3
#WE0	19	32	I/O2
#WP	20	31	I/O1
#WE1	21	30	I/O0
#WE2	22	29	#CE7
#WE3	23	28	#CE6
#WE4	24	27	#WE7
#WE5	25	26	#WE6



Name	Function
I/O0~I/O7	<b>DATA INPUTS/OUTPUTS</b> The I/O pins are used to input command, address and data, and to output data during read operations. The I/O pins float to high-z when the chip is deselected or when the outputs are disabled.
CLE	<b>COMMAND LATCH ENABLE</b> The CLE input controls the activating path for commands sent to the command register. When active high, commands are latched into the command register through the I/O ports on the rising edge of the WE signal.
#CE0	<b>Chip Enable Input</b> .When #CE <sub>n</sub> is Low, the command input cycle becomes valid. When #CE <sub>n</sub> is High, all inputs are ignored.
#CE1	
#CE2	
#CE3	
#CE4	

Name	Function
#CE5	
#CE6	
#CE7	
ALE	<p><b>ADDRESS LATCH ENABLE</b></p> <p>The ALE input controls the activating path for the address to the internal address registers. Addresses are latched on the rising edge of #WE with ALE high.</p>
#REn	<p><b>READ ENABLE</b></p> <p>The #REn input is the serial data-out control, and when active , drives the data onto the I/O bus. Data is valid <math>t_{REA}</math> after the falling edge of #RE which also increments the internal column address counter by one.</p>
#WEEn	<p><b>WRITE ENABLE</b></p> <p>The #WEEn input controls writes to the I/O port. Commands, address and data are latched on the rising edge of the #WE pulse.</p>
#WP	<p><b>WRITE PROTECT</b></p> <p>The #WP pin provides inadvertent write/erase protection during power transitions. The internal high voltage generator is reset when the #WP pin is active low.</p>
#RB0	<p><b>READY/BUSY OUTPUT</b></p> <p>The #R/Bn output indicates the status of the device operation. When low it indicates that a program, erase or random read operation is in process and returns to high state upon completion. It is an open drain output and does not float to high-z condition when the chip is deselected or when outputs are disabled.</p>
#RB1	
#RB2	
#RB3	
#RB4	
#RB5	
#RB6	
#RB7	
VCC	<b>POWER:</b> VCC is the power supply for device.
VSS	<b>GROUND</b>

## 5. ELECTRICAL SPECIFICATIONS

### 5.1. Absolute Maximum Ratings

Characteristics	Symbol	Maximum ratings	Unit
Voltage on VCC supply relative to Vss	$V_{CC}$	-0.6 to +4.6	V
Voltage on any pin relative to Vss	$V_{IN}$	-0.6 to +4.6	V
Power Dissipation	$P_D$	2.0	W
Operating Temperature Range	$T_{OPR}$	-55~ +125	°C
Storage Temperature Range	$T_{STG}$	-65 to +150	°C

### 5.2. Recommended DC Operating Conditions

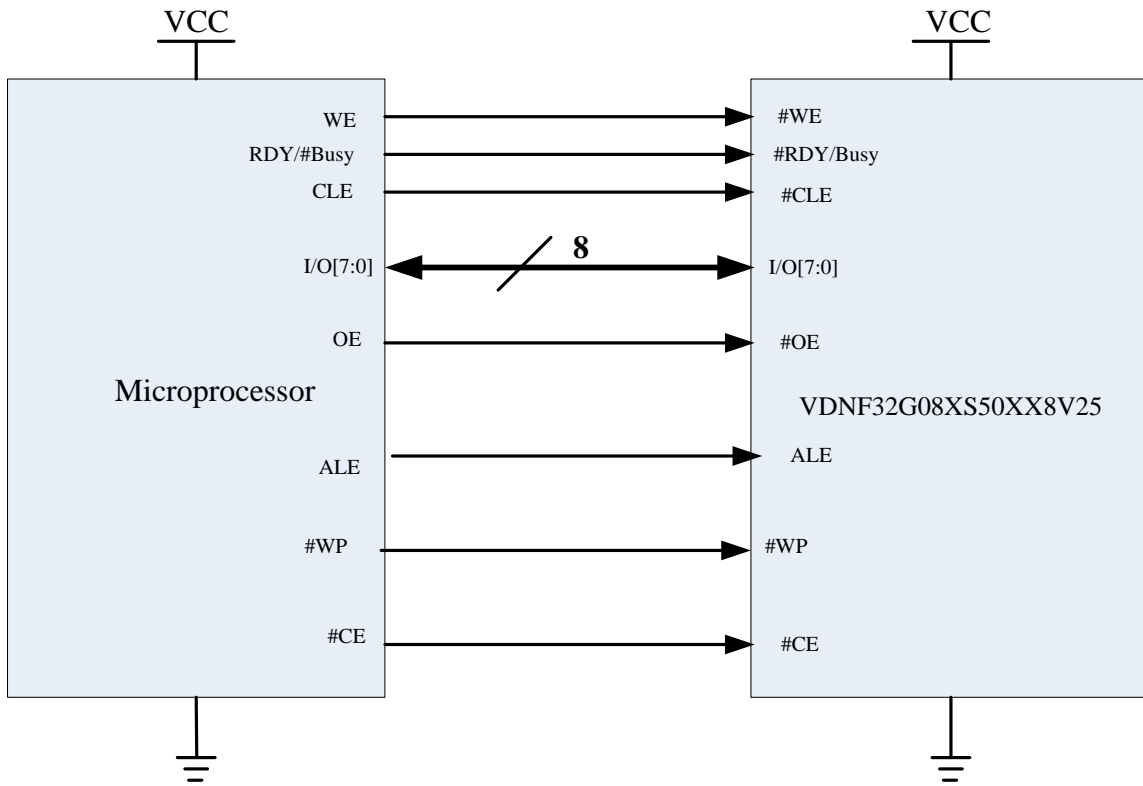
Parameter	Symbol	Min	Typ	Max	Unit
Supply voltage	$V_{CC}$	2.7	3.3	3.6	V
Input high voltage	$V_{IH}$	$V_{CC} \times 0.8$	—	$V_{CC} + 0.3$	V
Input low voltage	$V_{IL}$	-0.3	—	$V_{CC} \times 0.2$	V

### 5.3. DC And Operating Characteristics

Parameter	Symbol	Test Conditions	Min	Max	Unit
Output voltage low level	$V_{OL}$	$V_{CC}=3.6V, I_{OL}=4mA$	—	0.4	V
Output voltage high level	$V_{OH}$	$V_{CC}=2.7V, I_{OH}=-4mA$	2.4	—	V



## 6. Typical Application



## 7. ORDERING INFORMATION

1	2	3	4	5	6	7	8	9	10	11	12	13
<u>VD</u>	<u>NF</u>	<u>32G</u>	<u>08</u>	<u>X</u>	<u>S</u>	<u>50</u>	<u>X</u>	<u>X</u>	<u>8</u>	<u>V</u>	<u>25</u>	
VDIC												
NAND FLASH												
Capability: 32G bit												
Bus Width: 8 bit												
R= Radiation Data Tested; V= Generic Radiation Data Available												
Package: S=SOP												
50=50 Pin												
Temperature: E=0~70°C;I=-40~85°C;M=-55~125°C;S=Specific												
Quality: E= Sample; B= Industry; M=Military; S= Space												
Stacking Layer:8=8ayer												
Power Supply :V=3.3V												
Speed:25= 25ns												
-I、 -K or blank space=First Version												

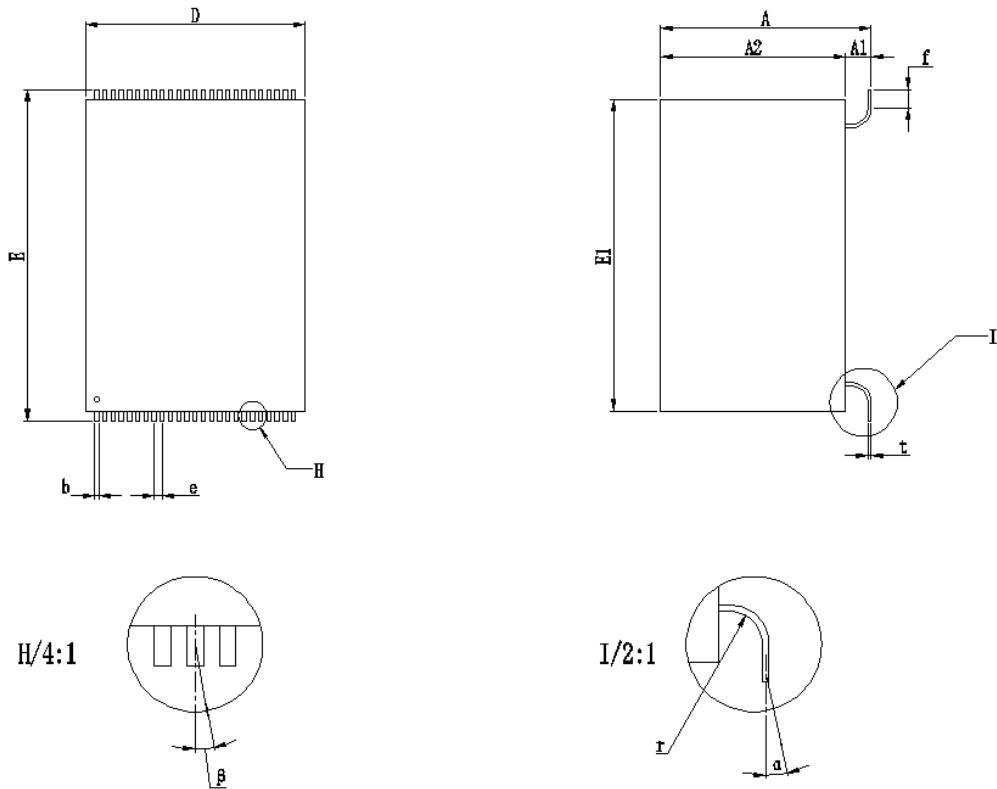
Part Number	Capacity (bit)	Bus Width (bit)	Radiation			Packaging	Temperature ( °C )
			TID <sup>1</sup>	SEL <sup>2</sup>	SEU <sup>3</sup>		
VDNF32G08VS50EE8V25	32G	8	-	-	-	SOP50	0 ~ +70
VDNF32G08VS50IB8V25	32G	8	-	-	-	SOP50	-40 ~ +85
VDNF32G08VS50MB8V25	32G	8	-	-	-	SOP50	-55 ~ +125
VDNF32G08VS50MM8V25	32G	8	-	-	-	SOP50	-55 ~ +125
VDNF32G08RS50MS8V25	32G	8	>60	>62.5	1.3	SOP50	-55 ~ +125

<sup>1</sup> TID: Total Dose (Krad(Si))

<sup>2</sup> SEL: LET Threshold (Mev.cm<sup>2</sup>/mg)

<sup>3</sup> SEU:SEU Threshold (Mev.cm<sup>2</sup>/mg)

### 8. PACKAGE DIMENSIONS



	Min	Max
A	12.30	12.80
A2	11.10	11.50
D	13.30	13.70
E	19.80	20.20
E1	18.80	19.20
f	1.20	
b	0.25	
e	0.50	
r	1.00	
t	0.20	
$\alpha$	$\leq 3^\circ$	
$\beta$	$\leq 3^\circ$	
<b>Notes :</b> 1. Unit : mm 2. A1= A - A2		

## 9. REVISION HISTORY

Revision	Date	Description of Change
A0	Nov 3,2015	First Created
A1	Mar 14,2016	Modified the PIN DESCRIPTIONS
A2	Aug 23,2016	Modified the ORDERING INFORMATION
A3	Jan 9,2017	Modified the PACKAGE DIMENSIONS
A4	Oct.25,2017	Changed company's name to Zhuhai Orbita Aerospace Science & Technology Co., Ltd
A5	Mar 24,2018	Add or reduce chapters